

1	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/602,804	MCILWAINE ET	AL.
	Examiner	Art Unit	-
	Quynh H. Nguyen	2614	

SEARCHED					
Class	Subclass	Date	Examiner		
379	265.01 265.02 265.05 266.07	6/7/06	QN		
above	updated	11/15/2006	QN		

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Searched: East, USPGPub, USPAT	6/7/06	QN
Inventor searched through PALM database	6/7/06	QN
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